Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/710,415	WEAVER, RICHARD LEE	
Examiner	Art Unit	
David M. Fenstermacher	3682	

	SEARCHED				
Class	Subclass	Date	Examiner		
74	845	7/26/2007	DMF		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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